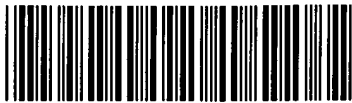


Search Notes

Application/Control No.

10/693,603

Examiner

ALI ALLAWI

Applicant(s)/Patent under
Reexamination

WERF ET AL.

Art Unit

2877

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched class 356 subclass 237	12/8/2005	AA
Searched for assignee for prior art publications	12/8/2005	AA
Searched discloses prior art by applicant	12/8/2005	AA
searched keywords such as lithographic process, defect detection, photo mask, refrence comparison	12/8/2005	AA